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### features

- Dual-Input, Single-Output MOSFET Switch With No Reverse Current Flow (No Parasitic Diodes)
- IN1...250-mΩ, 500-mA N-Channel; 16-μA Max Supply Current
- IN2...1.3-Ω, 10-mA P-Channel;
   1.5-μA Max Supply Current (V<sub>AUX</sub> Mode)
- Advanced Switch Control Logic
- CMOS- and TTL-Compatible Enable Input
- Controlled Rise, Fall, and Transition Times
- 2.7-V to 4 V Operating Range
- SOT-23-5 and SOIC-8 Package
- –40°C to 70°C Ambient Temperature Range
- 2-kV Human-Body-Model, 750-V CDM, 200-V Machine-Model Electrostatic-Discharge Protection

### typical applications

- Notebook and Desktop PCs
- Palmtops and PDAs

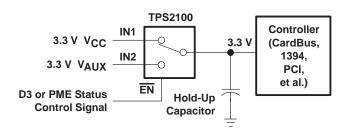


Figure 1. Typical Dual-Input Single-Output Application

### description

The TPS2100 and TPS2101 are dual-input, single-output power switches designed to provide uninterrupted output voltage when transitioning between two independent power supplies. Both devices combine one n-channel (250 m $\Omega$ ) and one p-channel (1.3  $\Omega$ ) MOSFET with a single output. The p-channel MOSFET (IN2) is used with auxiliary power supplies that deliver lower current for standby modes. The n-channel MOSFET (IN1) is used with a main power supply that delivers higher current required for normal operation. Low on-resistance makes the n-channel the ideal path for higher main supply current when power-supply regulation and system voltage drops are critical. When using the p-channel MOSFET, quiescent current is reduced to 0.75  $\mu$ A to decrease the demand on the standby power supply. The MOSFETs in the TPS2100 and TPS2101 do not have the parasitic diodes, found in discrete MOSFETs, which allow the devices to prevent back-flow current when the switch is off.

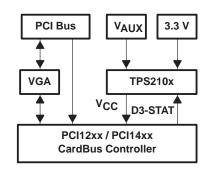
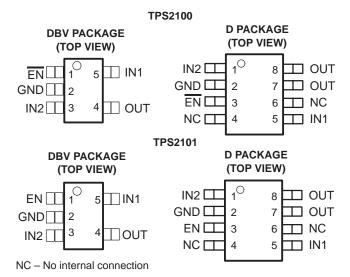


Figure 2. V<sub>AUX</sub> CardBus Implementation





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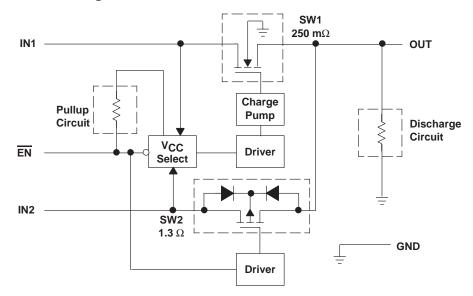
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AVAILABLE OPTIONS							
			PACKAGED DEVICES				
T <sub>J</sub> DEVICE		ENABLE	SOT-23-5 (DBV) <sup>†</sup>	SOIC-8 (D)			
-40°C to 85°C	TPS2100	EN	TSP2100DBV <sup>†</sup>	TPS2100D			
-40 C 10 85 C	TPS2101	EN	TPS2101DBV <sup>†</sup>	TPS2101D			

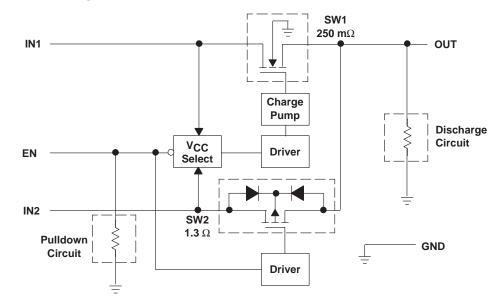
Both packages are available left-end taped and reeled. Add an R suffix to the D device type (e.g., TPS2101DR).

<sup>†</sup> Add T (e.g., TPS2100DBVT) to indicate tape and reel at order quantity of 250 parts. Add R (e.g., TPS2100DBVR) to indicate tape and reel at order quantity of 3000 parts.

### **TPS2100** functional block diagram



### **TPS2101** functional block diagram





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			Fund						
	TPS2100								
VIN1	VIN2	EN	OUT						
0 V	0 V	XX	GND						
0 V	3.3 V	L	GND						
3.3 V	3.3 V	L	VIN1						
3.3 V	0 V	L	VIN1						
0 V	3.3 V	Н	VIN2						
3.3 V	0 V	Н	VIN2						
3.3 V	3.3 V	Н	VIN2						

**Function Tables** 

100							
TPS2101							
VIN1	OUT						
0 V	0 V	XX	GND				
0 V	3.3 V	Н	GND				
3.3 V	3.3 V	Н	VIN1				
3.3 V	0 V	Н	VIN1				
0 V	3.3 V	L	VIN2				
3.3 V	0 V	L	VIN2				
3.3 V	3.3 V	L	VIN2				

XX = don't care

### **Terminal Functions**

TERMINAL						
		N	0.			DESCRIPTION
NAME	TPS2100		TPS2101		I/O	DESCRIPTION
	DBV	D	DBV	D		
EN			1	3		Active-high enable for IN1-OUT switch
EN	1	3			Ι	Active-low enable for IN1-OUT switch
GND	2	2	2	2	Ι	Ground
IN1	5	5	5	5	1	Main Input voltage, NMOS drain (250 m $\Omega$ )
IN2	3	1	3	1	1	Auxilliary input voltage, PMOS drain (1.3 $\Omega$ )
OUT	4	7, 8	4	7, 8	0	Power switch output
NC		4, 6		4, 6		No connection

### detailed description

#### power switches

#### n-channel MOSFET

The IN1-OUT n-channel MOSFET power switch has a typical on-resistance of 250 m $\Omega$  at 3.3-V input voltage, and is configured as a high-side switch.

### p-channel MOSFET

The IN2-OUT p-channel MOSFET power switch with typical on-resistance of 1.3  $\Omega$  at 3.3-V input voltage and is configured as a high-side switch. When operating, the p-channel MOSFET quiescent current is reduced to less than 1.5  $\mu$ A.

#### charge pump

An internal charge pump supplies power to the driver circuit and provides the necessary voltage to pull the gate of the MOSFET above the source. The charge pump operates from input voltages as low as 2.7 V and requires very little supply current.

#### driver

The driver controls the gate voltage of the IN1-OUT and IN2-OUT power switches. To limit large current surges and reduce the associated electromagnetic interference (EMI) produced, the drivers incorporate circuitry that controls the rise times and fall times of the output voltage.



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### detailed description (continued)

### enable

The logic enable will turn on the IN2-OUT power switch when a logic high is present on  $\overline{EN}$  (TPS2100) or logic low is present on EN (TPS2101). A logic low input on  $\overline{EN}$  (TPS2100) or logic high on EN (TPS2101) restores bias to the drive and control circuits and turns on the IN1-OUT power switch. The enable input is compatible with both TTL and CMOS logic levels.

### the VAUX application for CardBus controllers

The PC Card specification requires the support of  $V_{AUX}$  to the CardBus controller as well as to the PC Card sockets. Both are 3.3-V requirements; however the CardBus controller's current demand from the  $V_{AUX}$  supply is limited to 10 µA, whereas the PC Card may consume as much as 200 mA. In either implementation, if support of a wake-up event is required, the controller and the socket will transition from the 3.3-V  $V_{CC}$  rail to the 3.3-V  $V_{AUX}$  rail when the equipment moves into a low power mode such as D3. The transition from  $V_{CC}$  to  $V_{AUX}$  needs to be seamless in order to maintain all memory and register information in the system. If  $V_{AUX}$  is not supported, the system will lose all register information when it transitions to the D3 state.

### absolute maximum ratings over operating free-air temperature (unless otherwise noted)<sup>†</sup>

Input voltage range, V <sub>I(IN1)</sub> (see Note1)	
Input voltage range, V <sub>I(IN2)</sub> (see Note1)	
Input voltage range, Vi at ÉN or EN	
Output voltage range, V <sub>O</sub> (see Note 1)	0.3 V to 5 V
Continuous output current, I <sub>O(IN1</sub> )	700 mA
Continuous output current, I <sub>O(IN2)</sub>	
Continuous total power dissipation	See dissipation rating table
Operating virtual junction temperature range, T <sub>J</sub>	
Storage temperature range, T <sub>stg</sub>	–65°C to 150°C
Lead temperature soldering 1,6 mm (1/16 inch) from case for 10 seconds	260°C
Electrostatic discharge (ESD) protection: Human body model	
Machine model	200 V
Charged device model (CDM)	

<sup>†</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.
NOTE 1: All voltages are with respect to GND.

#### DISSIPATION RATING TABLE

PACKAGE	T <sub>A</sub> < 25°C POWER RATING	DERATING FACTOR ABOVE T <sub>A</sub> = 25°C	T <sub>A</sub> = 70°C POWER RATING	T <sub>A</sub> = 85°C POWER RATING	
DBV	309 mW	3.1 mW/°C	170 mW	123 mW	
D	568 mW	5.7 mW/°C	313 mW	227 mW	

### recommended operating conditions

	MIN	MAX	UNIT
Input voltage, VI(INx)	2.7	4	V
Input voltage, VI at EN and EN	0	4	V
Continuous output current, IO(IN1)		500	mA
Continuous output current, IO(IN2)		100‡	mA
Operating virtual junction temperature, TJ	-40	85	°C

<sup>‡</sup> The device can deliver up to 220 mA at I<sub>O(IN2)</sub>. However, operation at the higher current levels will result in greater voltage drop across the device, and greater voltage droop when switching between IN1 and IN2.



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# electrical characteristics over recommended operating junction temperature range, $V_{I(IN1)} = V_{(IN2)} = 3.3 \text{ V}$ , $I_{O}$ = rated current (unless otherwise noted)

power switch

PARAMETER	TEST CONDITIONS <sup>†</sup>	MIN	ТҮР	MAX	UNIT		
	IN1-OUT	TJ = 25°C		250		mΩ	
rps(on) On-state resistance		TJ = 85°C		300	375	11152	
rDS(on) On-state resistance	IN2-OUT	TJ = 25°C		1.3		Ω	
	IN2-001	TJ = 85°C		1.5	2.1		

<sup>†</sup>Pulse-testing techniques maintain junction temperature close to ambient termperature; thermal effects must be taken into account separately.

### enable input (EN and EN)

PARAMETER TEST CONI			EST CONDITIONS	MIN	TYP	MAX	UNIT
VIH	High-level input voltage	$2.7 \text{ V} \leq \text{V}_{I(INx)} \leq 4 \text{ V}$		2			V
VIL	Low-level input voltage	$2.7 V \leq V_{I(INx)} \leq 4 V$				0.8	V
1.	Input current	TPS2100	$EN = 0 V \text{ or } EN = V_{I(INx)}$	-0.5		0.5	μΑ
'	input current	TPS2101	$EN = 0 V \text{ or } EN = V_{I(INx)}$	-0.5		0.5	μA

#### supply current

	PARAMETER	TEST CONDITIONS			MIN	TYP	MAX	UNIT	
			$\overline{\text{EN}} = \text{H},$	TJ = 25°C		0.75		μA	
		TPS2100	IN2 selected	$-40^\circ C \le T_J \le 85^\circ C$			1.5		
		1952100	$\overline{EN} = L,$ IN1 selected	TJ = 25°C		10		μA	
	Supply ourroat			$-40^\circ C \le T_J \le 85^\circ C$			16		
11	Supply current	TPS2101	TPS2101 $EN = H,$ EN = H,	$T_J = 25^{\circ}C$		0.75		μΑ	
				$-40^\circ C \le T_J \le 85^\circ C$			1.5		
				$T_J = 25^{\circ}C$		10			
				$-40^\circ C \le T_J \le 85^\circ C$			16	μA	



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# switching characteristics, $T_J = 25^{\circ}C$ , $V_{I(IN1)} = V_{I(IN2)} = 3.3 V$ (unless otherwise noted)<sup>†</sup>

			/ (((12)	-					
	PARAMETER		TE	TEST CONDITIONS <sup>†</sup>			MAX	UNIT	
				$C_L = 1 \mu F$ ,	IL = 500 mA	830			
		IN1-OUT	$V_{I(IN2)} = 0$	$C_L = 10 \ \mu F$ ,	I <sub>L</sub> = 500 mA	840			
+	Output rice time			$C_L = 1 \mu F$ ,	I <sub>L</sub> = 10 mA	640			
t <sub>r</sub>	Output rise time			$C_L = 1 \mu F$ ,	IL = 10 mA	5.5		μs	
		IN2-OUT	$V_{I(IN1)} = 0$	$C_L = 10 \ \mu F$ ,	IL = 10 mA	70			
				$C_L = 1 \mu F$ ,	IL = 1 mA	5.5			
		IN1-OUT	V <sub>I(IN2)</sub> = 0	$C_L = 1 \ \mu F$ ,	IL = 500 mA	8		μs	
				$C_L = 10 \ \mu\text{F},$	IL = 500 mA	93			
+.				$C_L = 1 \mu F$ ,	I <sub>L</sub> = 10 mA	23			
tf	Output fall time	IN2-OUT	VI(IN1) = 0	$C_L = 1 \ \mu F$ ,	IL = 10 mA	690			
				$C_L = 10 \ \mu F$ ,	IL = 10 mA	6900			
				$C_L = 1 \mu F$ ,	IL = 1 mA	6900			
+	Brongation delouting low to high output	IN1-OUT	$V_{I(IN2)} = 0$	Ci = 10 IIE	h - 10 mA	75			
<sup>t</sup> PLH	Propagation delay time, low-to-high output	IN2-OUT	$V_{I(IN1)} = 0$	C <sub>L</sub> = 10 μF,		2		μs	
tou	Propagation delay time, high-to-low output	IN1-OUT	$V_{I(IN2)} = 0$	C <sub>L</sub> = 10 μF,	h = 10  mA	3			
<sup>t</sup> PHL	- Topagation delay time, high-to-tow output	IN2-OUT	$V_{I(IN1)} = 0$	$C_{L} = 10 \mu$ F,		370		μs	

<sup>†</sup> All timing parameters refer to Figure 3.



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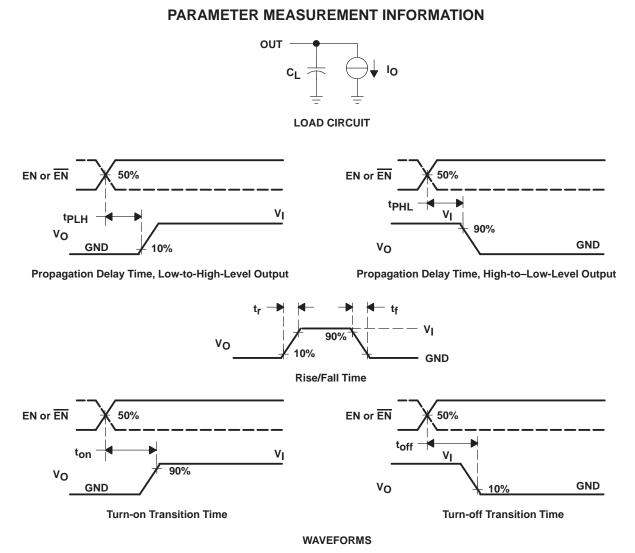


Figure 3. Test Circuit and Voltage Waveforms

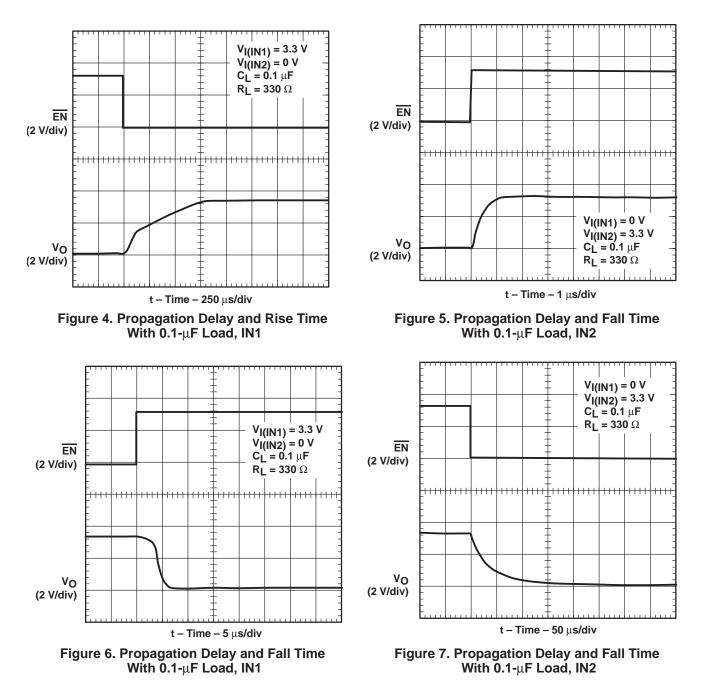
### Table of Timing Diagrams<sup>†</sup>

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Propagation Delay and Rise Time With 0.1- $\mu$ F Load, IN1	4
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Propagation Delay and Fall Time With 0.1- $\mu$ F Load, IN1	6
Propagation Delay and Fall Time With 0.1- $\mu$ F Load, IN2	7
Propagation Delay and Rise Time With $1-\mu F$ Load, IN1	8
Propagation Delay and Rise Time With $1-\mu F$ Load, IN2	9
Propagation Delay and Fall Time With 1- $\mu$ F Load, IN1	10
Propagation Delay and Fall Time With 1- $\mu$ F Load, IN2	11

<sup>†</sup> Waveforms shown in Figures 4–11 refer to TPS2100 at  $T_J = 25^{\circ}C$ 



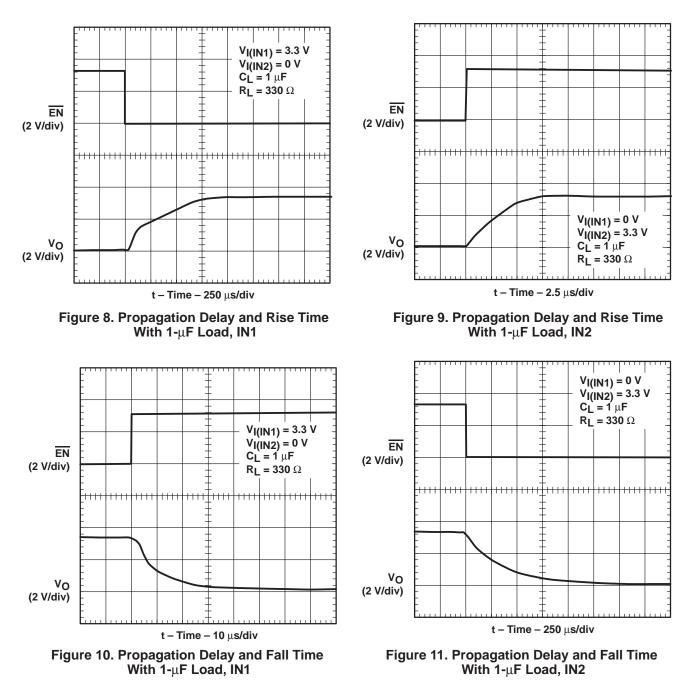
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### PARAMETER MEASUREMENT INFORMATION



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PARAMETER MEASUREMENT INFORMATION

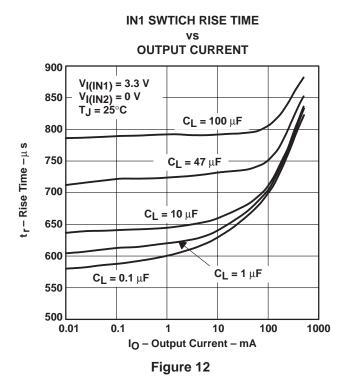


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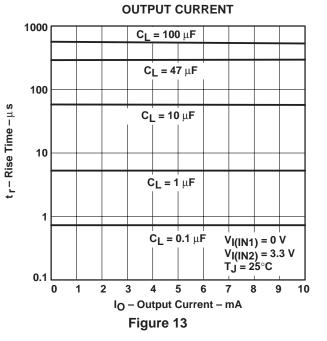
### TYPICAL CHARACTERISTICS

### **Table of Graphs**

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IN2 Supply Current	vs Junction Temperature (IN2 Disabled)	21
IN1-OUT On-State Resistance	vs Junction Temperature	22
IN2-OUT On-State Resistance	vs Junction Temperature	23



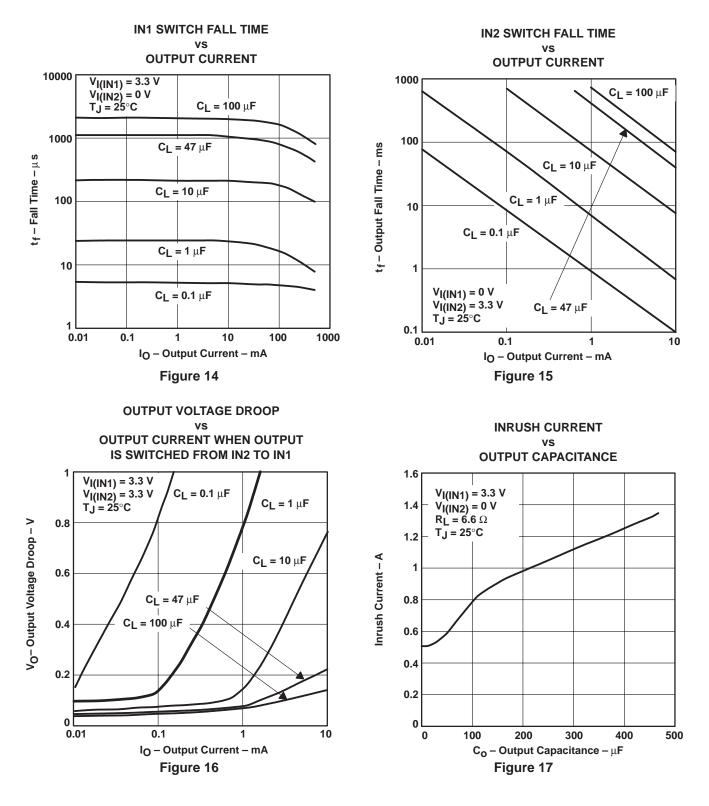
#### IN2 SWTICH RISE TIME vs





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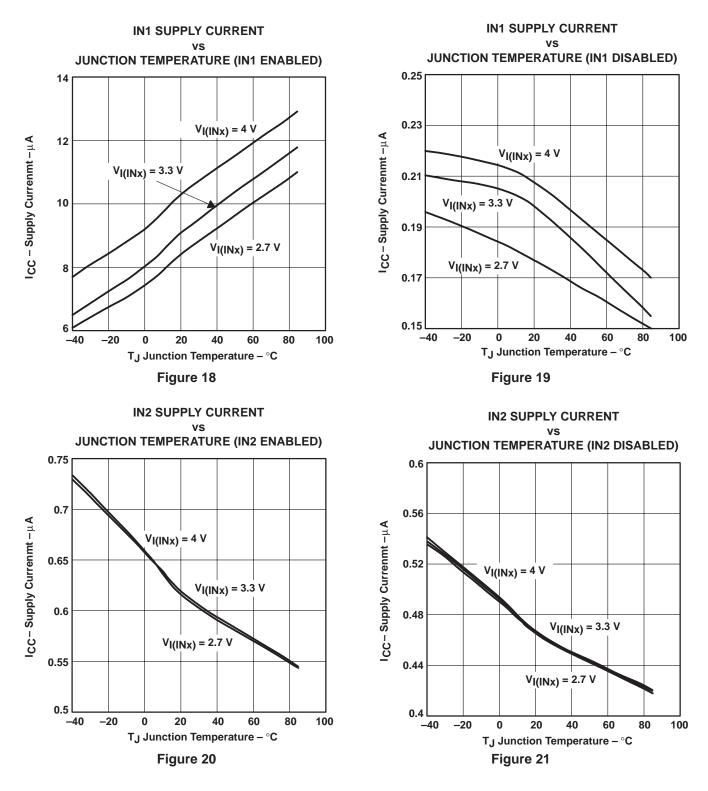
### **TYPICAL CHARACTERISTICS**





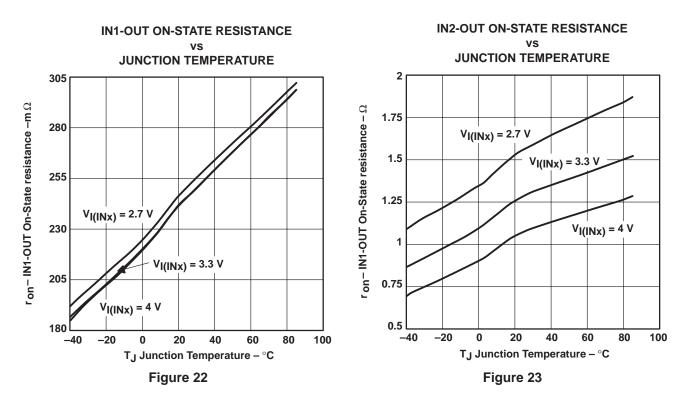
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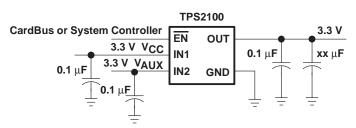


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### **TYPICAL CHARACTERISTICS**

### **APPLICATION INFORMATION**





### power supply considerations

A 0.01- $\mu$ F to 0.1- $\mu$ F ceramic bypass capacitor between IN and GND, close to the device is recommended. The output capacitor should be chosen based on the size of the load during the transition of the switch. A 47- $\mu$ F capacitor is recommended for 10-mA loads. Typical output capacitors (xx  $\mu$ F, shown in Figure 24) required for a given load can be determined from Figure 16 which shows the output voltage droop when output is switched from IN2 to IN1. The output voltage droop is insignificant when output is switched from IN1 to IN2. Additionally, bypassing the output with a 0.01- $\mu$ F to 0.1- $\mu$ F ceramic capacitor improves the immunity of the device to short-circuit transients.



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### **APPLICATION INFORMATION**

### power supply considerations (continued)

### switch transition

The n-channel MOSFET on IN1 uses a charge-pump to create the gate-drive voltage, which gives the IN1 switch a rise time of approximately 1 ms. The p-channel MOSFET on IN2 has a simpler drive circuit that allows a rise time of approximately 8  $\mu$ s. Because the device has two switches and a single enable pin, these rise times are seen as transition times, from IN1 to IN2, or IN2 to IN1, by the output. The controlled transition times help limit the surge currents seen by the power supply during switching.

### thermal protection

Thermal protection provided on the IN1 switch prevents damage to the IC when heavy-overload or short-circuit faults are present for extended periods of time. The increased dissipation causes the junction temperature to rise to dangerously high levels. The protection circuit senses the junction temperature of the switch and shuts it off at approximately 125°C (T<sub>J</sub>). The switch remains off until the junction temperature has dropped. The switch continues to cycle in this manner until the load fault or input power is removed.

#### undervoltage lockout

An undervoltage lockout function is provided to ensure that the power switch is in the off state at power-up. Whenever the input voltage falls below approximately 2 V, the power switch quickly turns off. This function facilitates the design of hot-insertion systems that may not have the capability to turn off the power switch before input power is removed. Upon reinsertion, the power switch will be turned on with a controlled rise time to reduce EMI and voltage overshoots.

### power dissipation and junction temperature

The low on-resistance on the n-channel MOSFET allows small surface-mount packages, such as SOIC, to pass large currents. The thermal resistances of these packages are high compared to that of power packages; it is good design practice to check power dissipation and junction temperature. First, find  $r_{on}$  at the input voltage, and operating temperature. As an initial estimate, use the highest operating ambient temperature of interest and read  $r_{on}$  from Figure 22 or Figure 23. Next calculate the power dissipation using:

$$P_{D} = r_{on} \times I^{2}$$

Finally, calculate the junction temperature:

$$T_J = P_D \times R_{\theta JA} + T_A$$

Where:

 $T_A$  = Ambient temperature

 $R_{\theta,IA}$  = Thermal resistance

Compare the calculated junction temperature with the initial estimate. If they do not agree within a few degrees, repeat the calculation using the calculated value as the new estimate. Two or three iterations are generally sufficient to obtain a reasonable answer.

### **ESD** protection

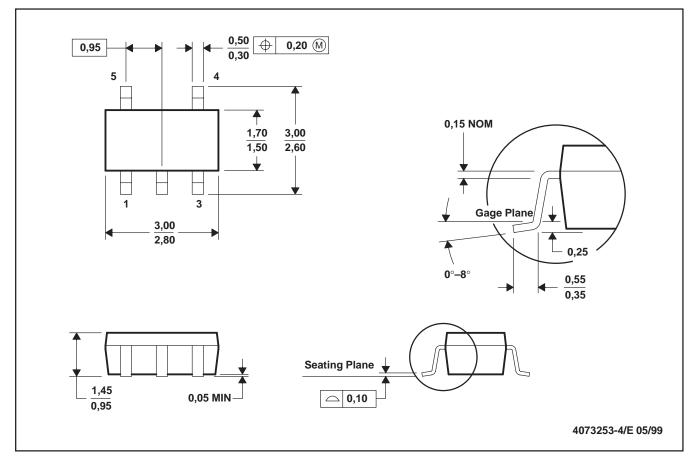
All TPS2100 and TPS2101 terminals incorporate ESD-protection circuitry designed to withstand a 2-kV human-body-model discharge as defined in MIL-STD-883C.



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### MECHANICAL DATA

### PLASTIC SMALL-OUTLINE



NOTES: A. All linear dimensions are in millimeters.

DBV (R-PDSO-G5)

- B. This drawing is subject to change without notice.
- C. Body dimensions do not include mold flash or protrusion.
- D. Falls within JEDEC MO-178



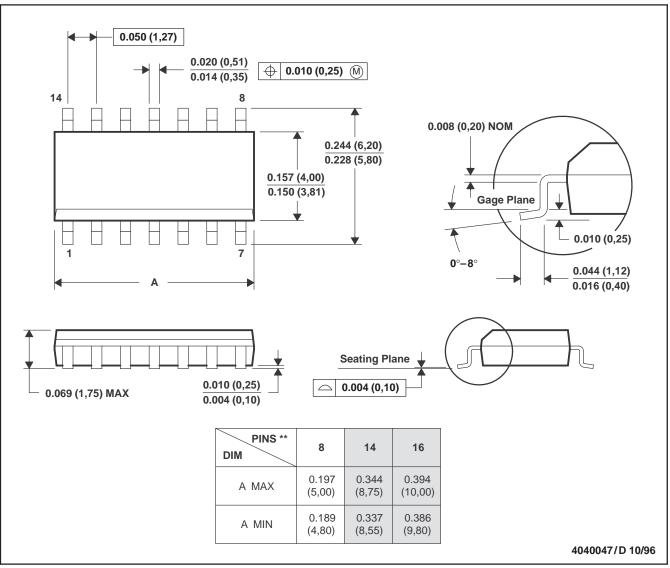
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**MECHANICAL DATA** 

### D (R-PDSO-G\*\*)

#### PLASTIC SMALL-OUTLINE PACKAGE





NOTES: A. All linear dimensions are in inches (millimeters).

B. This drawing is subject to change without notice.

C. Body dimensions do not include mold flash or protrusion, not to exceed 0.006 (0,15).

D. Falls within JEDEC MS-012



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